

APS-U Workshop: High-Energy X-ray Microscope (HEXM)  
April 28, 2017

Morning Session: 8:30 – 12:00  
Chair: Jun-Sang Park, APS

8:30-9:00 Dean Haeffner, APS-U, *Overview of APS-U Project*

9:00-9:40 Sarvjit Shastri, APS, *HEXM Beamline – preliminary design*

9:40-10:15 Jonathan Almer, APS, *HEXM Beamline – scientific scope*

10:15-10:30 Coffee Break

10:30-11:00 Stuart Stock, Northwestern U, *Diffraction-based imaging – scattering tomography*

11:00-11:30 Joel Bernier, LLNL, *Diffraction-based imaging- high-energy diffraction microscopy*

11:30-12:00 Peter Kenesei, APS, *Direct-beam imaging – tomography and TXM*

Lunch 12:00-1:00

Afternoon Session: 1:00 - 5:00  
Chair: Jonathan Almer, APS

1:00-1:30 Stephan Hruszkewycz, ANL-MSD, *Coherent diffraction imaging at high x-ray energies*

1:30-2:00 Paul Shade, AFRL, *Advanced environments*

2:00-2:30 Mike Sangid, Purdue U, *Merging HEXM data with materials models*

2:30-2:45 Coffee Break

2:45-3:15 Don Brown, LANL, *Advanced Manufacturing*

3:15-3:45 Yan Gao, GE-GR, *Industrial Perspective*

3:45-4:15 Meimei Li, ANL-NE, *Activated Materials Lab*

4:15-4:45 Mike Pellin, ANL, *XMAT Project*

4:45-5:00 Final discussion and adjourn